

# BUL128D-B

## HIGH VOLTAGE FAST-SWITCHING NPN POWER TRANSISTOR

- STMicroelectronics PREFERRED SALES **TYPE**
- NPN TRANSISTOR
- HIGH VOLTAGE CAPABILITY
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR **RELIABLE OPERATION**
- VERY HIGH SWITCHING SPEED
- INTEGRATED ANTIPARALLEL **COLLECTOR-EMITTER DIODE**

#### **APPLICATIONS**

- **ELECTRONIC BALLAST FOR** FLUORESCENT LIGHTING
- FLYBACK AND FORWARD SINGLE TRANSISTOR LOW POWER CONVERTERS



The device is manufactured using high voltage Multi Epitaxial Planar technology for high switching speeds and medium voltage capability. It uses a Cellular Emitter structure with planar edge termination to enhance switching speeds while maintaining the wide RBSOA.

The device is designed for use in lighting applications and low cost switch-mode power supplies.

Figure 1: Package

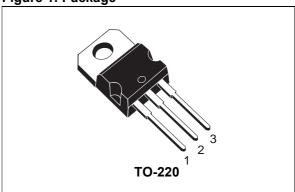
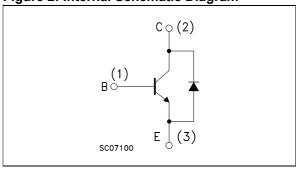


Figure 2: Internal Schematic Diagram



**Table 1: Order Codes** 

Part Number	Marking	Package	Packaging	
BUL128D-B	BUL128D-B	TO-220	Tube	

**Table 2: Absolute Maximum Ratings** 

Symbol	Parameter	Value	Unit
V <sub>CES</sub>	Collector-Emitter Voltage (V <sub>BE</sub> = 0)	700	V
V <sub>CEO</sub>	Collector-Emitter Voltage (I <sub>B</sub> = 0)	400	V
V <sub>EBO</sub>	Emitter-Base Voltage	V <sub>(BR)EBO</sub>	V
	$(I_C = 0, I_B = 2 A, t_p < 10 \mu s, T_J = 150  {}^{\circ}C)$		
I <sub>C</sub>	Collector Current	4	Α
I <sub>CM</sub>	Collector Peak Current (t <sub>p</sub> < 5ms)	8	Α
I <sub>B</sub>	Base Current	2	Α
I <sub>BM</sub>	Base Peak Current (t <sub>p</sub> < 5ms)	4	Α

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Symbol	Parameter	Value	Unit
P <sub>tot</sub>	Total Dissipation at T <sub>C</sub> = 25 °C	70	W
T <sub>stg</sub>	Storage Temperature	-65 to 150	°C
T <sub>J</sub>	Max. Operating Junction Temperature	150	°C

#### **Table 3: Thermal Data**

R <sub>thj-case</sub>	Thermal Resistance Junction-Case	Max	1.78	°C/W
R <sub>thj-amb</sub>	Thermal Resistance Junction-Ambient	Max	62.5	°C/W

# Table 4: Electrical Characteristics (T<sub>case</sub> = 25 °C unless otherwise specified)

Symbol	Parameter Test Conditions		Parameter Test Conditions Mi		Тур.	Max.	Unit
I <sub>CES</sub>	Collector Cut-off Current	V <sub>CE</sub> = 700 V				100	μΑ
	(V <sub>BE</sub> = 0 V)	V <sub>CE</sub> =700 V	T <sub>j</sub> = 125 °C			500	μA
I <sub>CEO</sub>	Collector Cut-off Current	V <sub>CE</sub> = 400 V				250	μΑ
	$(I_B = 0)$						
$V_{(BR)EBO}$	Emitter-Base Breakdown Voltage	I <sub>E</sub> = 10 mA		9		18	V
	$(I_C = 0)$						
V <sub>CEO(sus)</sub> *	Collector-Emitter Sustaining Voltage	I <sub>C</sub> = 100 mA	L = 25 mH	400			V
	$(I_B = 0)$						
V <sub>CE(sat)</sub> *	Collector-Emitter	I <sub>C</sub> = 0.5 A	I <sub>B</sub> = 0.1 A			0.7	V
	Saturation Voltage	I <sub>C</sub> = 1 A	$I_{B} = 0.2 A$			1	V
		I <sub>C</sub> = 2.5 A	I <sub>B</sub> = 0.5 A			1.5	V
		I <sub>C</sub> = 4 A	I <sub>B</sub> = 1 A		0.5		V
V <sub>BE(sat)</sub> *	Base-Emitter Saturation	I <sub>C</sub> = 0.5 A	I <sub>B</sub> = 0.1 A			1.1	V
	Voltage	I <sub>C</sub> = 1 A	$I_B = 0.2 A$			1.2	V
		I <sub>C</sub> = 2.5 A	$I_{B} = 0.5 A$			1.3	V
h <sub>FE</sub> *	DC Current Gain	I <sub>C</sub> = 10 mA	V <sub>CE</sub> = 5 V	10			
		I <sub>C</sub> = 2 A	$V_{CE} = 5 V$	12		32	
	RESISTIVE LOAD	V <sub>CC</sub> =200 V	I <sub>C</sub> = 2 A				
$t_s$	Storage Time	I <sub>B1</sub> = 0.4 A	$V_{BE(off)} = -5 V$		0.6		μs
t <sub>f</sub>	Fall Time	$R_{BB} = 0 \Omega$	L = 200 µH		0.1		μs
		(see figure 15)					
	INDUCTIVE LOAD	V <sub>CC</sub> =250 V	I <sub>C</sub> = 2 A				
$t_s$	Storage Time	I <sub>B1</sub> = 0.4 A	$I_{B2} = -0.4 \text{ A}$	2		2.9	μs
t <sub>f</sub>	Fall Time	Tp = 30 μs	(see figure 14)		0.2		μs

<sup>\*</sup> Pulsed: Pulsed duration = 300  $\mu$ s, duty cycle  $\leq$  1.5 %.

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Figure 3: Safe Operating Area

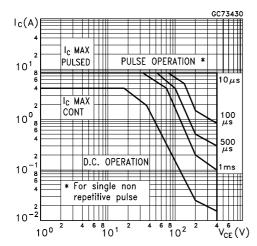


Figure 4: DC Current Gain

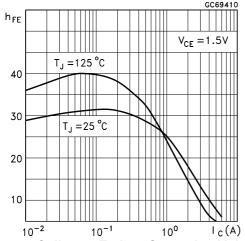


Figure 5: Collector-Emitter Saturation Voltage

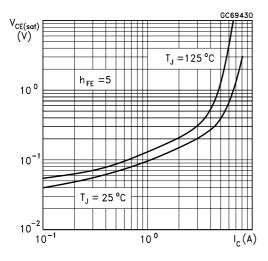


Figure 6: Derating Current

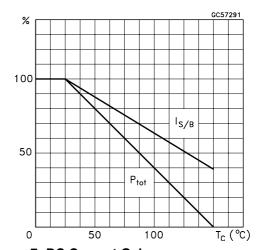


Figure 7: DC Current Gain

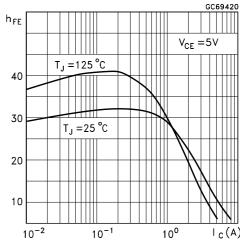


Figure 8: Base-Emitter Saturation Voltage

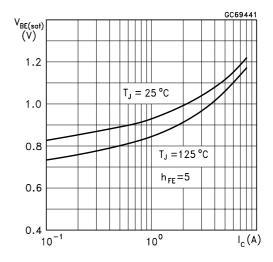


Figure 9: Inductive Load Fall Time

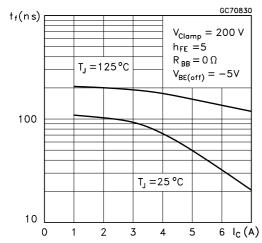


Figure 10: Resistive Load Fall Time

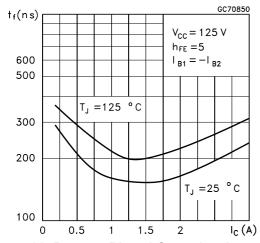


Figure 11: Reverse Biased Operating Area

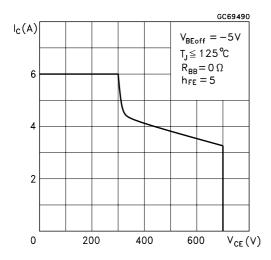


Figure 12: Inductive Load Stoarage Time

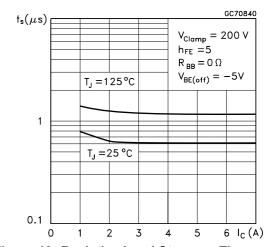
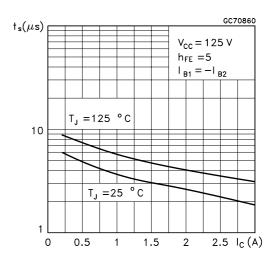
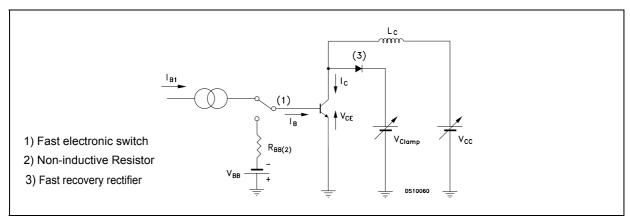


Figure 13: Resistive Load Stoarage Time

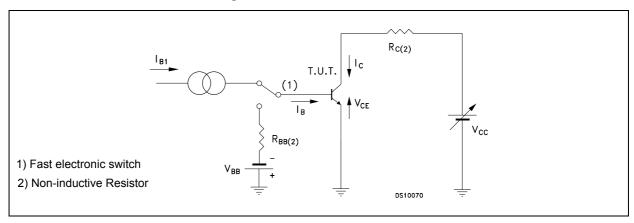


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Figure 14: Inductive Load Switching Test Circuit

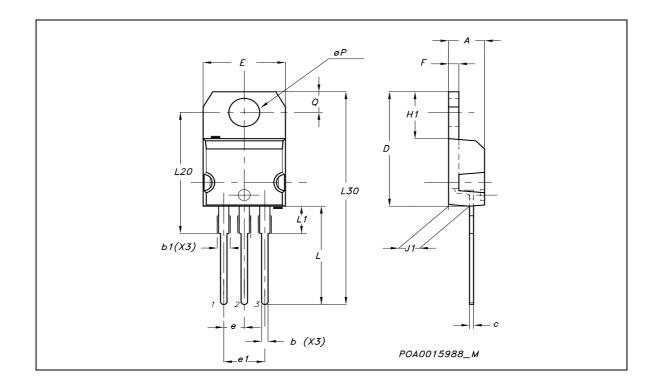


**Table 15: Restistive Load Switching Test Circuit** 



## **TO-220 MECHANICAL DATA**

DIM.		mm.			inch		
DIN.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.	
A	4.40		4.60	0.173		0.181	
b	0.61		0.88	0.024		0.034	
b1	1.15		1.70	0.045		0.066	
С	0.49		0.70	0.019		0.027	
D	15.25		15.75	0.60		0.620	
E	10		10.40	0.393		0.409	
е	2.40		2.70	0.094		0.106	
e1	4.95		5.15	0.194		0.202	
F	1.23		1.32	0.048		0.052	
H1	6.20		6.60	0.244		0.256	
J1	2.40		2.72	0.094		0.107	
L	13		14	0.511		0.551	
L1	3.50		3.93	0.137		0.154	
L20		16.40			0.645		
L30		28.90			1.137		
øΡ	3.75		3.85	0.147		0.151	
Q	2.65		2.95	0.104		0.116	



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## Table 5:

Version	Release Date	Change Designator
01-Oct-2002	1	First Release.
15-Feb-2005	1	Added table 1 on page 1.

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